74ABT821

10-bit D-type flip-flop; positive-edge trigger; 3-state

Rev. 03 — 25 February 2010 Product

Product data sheet

1. **General description**

The 74ABT821 high-performance BiCMOS device combines low static and dynamic power dissipation with high speed and high output drive.

The 74ABT821 bus interface register is designed to eliminate the extra packages required to buffer existing registers and provide extra data width for wider data/address paths of buses carrying parity.

The 74ABT821 is a buffered 10-bit wide version of the 74ABT374A.

The 74ABT821 is a 10-bit, edge-triggered register coupled to ten 3-state output buffers. The device is controlled by the clock (CP) and output enable (\overline{OE}) control gates.

The register is fully edge triggered. The state of each D input, one set-up time before the LOW-to-HIGH clock transition is transferred to the corresponding output Q of the flip-flop.

The 3-state output buffers are designed to drive heavily loaded 3-state buses, MOS memories, or MOS microprocessors.

The active LOW output enable (OE) controls all ten 3-state buffers independent of the register operation. When $\overline{\text{OE}}$ is LOW, the data in the register appears at the outputs. When $\overline{\text{OE}}$ is HIGH, the outputs are in high-impedance OFF-state, which means they will neither drive nor load the bus.

Features and benefits 2.

- High-speed parallel registers with positive-edge triggered D-type flip-flops
- Ideal where high speed, light loading, or increased fan-in are required with MOS microprocessors
- Output capability: +64 mA and -32 mA
- Power-on 3-state
- Power-on reset
- Latch-up protection exceeds 500 mA per JESD78B class II level A
- ESD protection:
 - HBM JESD22-A114F exceeds 2000 V
 - MM JESD22-A115-A exceeds 200 V



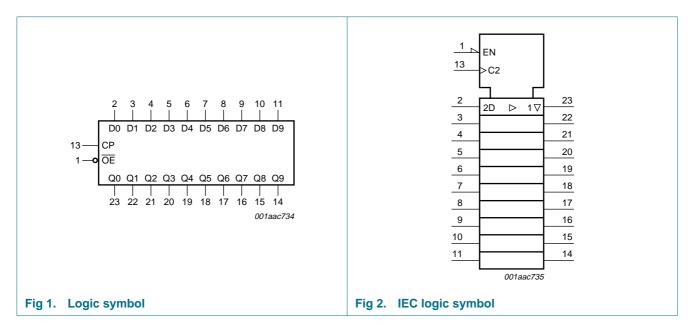
10-bit D-type flip-flop; positive-edge trigger; 3-state

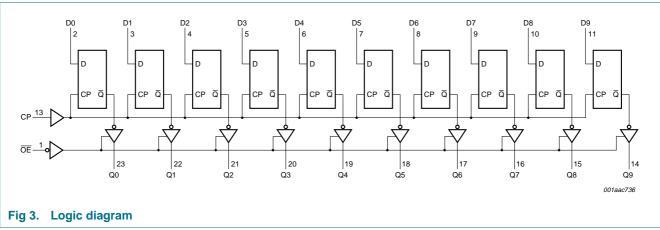
3. Ordering information

Table 1. Ordering information

| Type number | Package | | | |
|-------------------------|-------------------|---------|------------------------------------------------------------------------|----------|
| 74ABT821D 74ABT821DB | Temperature range | Name | Description | Version |
| 74ABT821D | –40 °C to +85 °C | SO24 | plastic small outline package; 24 leads; body width 7.5 mm | SOT137-1 |
| 74ABT821DB | –40 °C to +85 °C | SSOP24 | plastic shrink small outline package; 24 leads; body width 5.3 mm | SOT340-1 |
| 74ABT821PW | –40 °C to +85 °C | TSSOP24 | plastic thin shrink small outline package; 24 leads; body width 4.4 mm | SOT355-1 |

4. Functional diagram

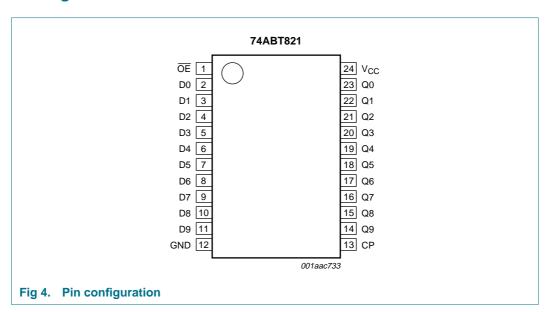




10-bit D-type flip-flop; positive-edge trigger; 3-state

5. Pinning information

5.1 Pinning



5.2 Pin description

Table 2. Pin description

| Symbol | Pin | Description |
|-----------------|----------------------------------------|----------------------------------------|
| ŌĒ | 1 | output enable input (active LOW) |
| D0 to D9 | 2, 3, 4, 5, 6, 7, 8, 9, 10, 11 | data input |
| GND | 12 | ground (0 V) |
| СР | 13 | clock pulse input (active rising edge) |
| Q0 to Q9 | 23, 22, 21, 20, 19, 18, 17, 16, 15, 14 | data output |
| V _{CC} | 24 | supply voltage |

10-bit D-type flip-flop; positive-edge trigger; 3-state

6. Functional description

6.1 Function table

Table 3. Function table^[1]

| Input | | | Internal register | Output | Operating mode |
|-------|------------|----------|-------------------|----------|-----------------|
| OE | СР | D0 to D9 | | Q0 to Q9 | |
| L | \uparrow | I | L | L | load and read |
| L | \uparrow | h | Н | Н | register |
| L | NC | X | NC | NC | hold |
| Н | NC | Χ | NC | Z | disable outputs |
| Н | ↑ | Dn | Dn | Z | |

^[1] H = HIGH voltage level;

h = HIGH voltage level one set-up time prior to the LOW-to-HIGH clock transition;

L = LOW voltage level;

I = LOW voltage level one set-up time prior to the LOW-to-HIGH clock transition;

NC = no change;

X = don't care;

Z = high-impedance OFF-state;

 \uparrow = LOW-to-HIGH clock transition.

10-bit D-type flip-flop; positive-edge trigger; 3-state

7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | Min | Max | Unit |
|------------------|-------------------------|-----------------------------------|-----------------|------|------|
| V_{CC} | supply voltage | | -0.5 | +7.0 | V |
| V_{I} | input voltage | | <u>[1]</u> –1.2 | +7.0 | V |
| V_{O} | output voltage | output in OFF-state or HIGH-state | <u>[1]</u> –0.5 | +5.5 | V |
| I _{IK} | input clamping current | V _I < 0 V | -18 | - | mA |
| I _{OK} | output clamping current | V _O < 0 V | -50 | - | mA |
| I _O | output current | output in LOW-state | - | 128 | mA |
| Tj | junction temperature | | [2] _ | 150 | °C |
| T _{stg} | storage temperature | | -65 | +150 | °C |

^[1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

8. Recommended operating conditions

Table 5. Recommended operating conditions

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|------------------|-------------------------------------|-------------|-----|-----|----------|------|
| V_{CC} | supply voltage | | 4.5 | - | 5.5 | V |
| V_{I} | input voltage | | 0 | - | V_{CC} | V |
| V_{IH} | HIGH-level input voltage | | 2.0 | - | - | V |
| V_{IL} | LOW-level input voltage | | - | - | 8.0 | V |
| I _{OH} | HIGH-level output current | | -32 | - | - | mA |
| I_{OL} | LOW-level output current | | - | - | 64 | mA |
| Δt/ΔV | input transition rise and fall rate | | 0 | - | 5 | ns/V |
| T _{amb} | ambient temperature | in free air | -40 | - | +85 | °C |

^[2] The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150 °C.

10-bit D-type flip-flop; positive-edge trigger; 3-state

9. Static characteristics

Table 6. Static characteristics

| Symbol | Parameter | Conditions | | | 25 °C | | –40 °C t | o +85 °C | Unit |
|-----------------------|------------------------------------|-------------------------------------------------------------------------------------------------|------------|------|-------|------|----------|----------|------|
| | | | | Min | Тур | Max | Min | Max | |
| V _{IK} | input clamping voltage | $V_{CC} = 4.5 \text{ V}; I_{IK} = -18 \text{ mA}$ | | -1.2 | -0.9 | - | -1.2 | - | V |
| V _{OH} | HIGH-level output | $V_I = V_{IL}$ or V_{IH} | | | | | | | |
| | voltage | $V_{CC} = 4.5 \text{ V}; I_{OH} = -3 \text{ mA}$ | | 2.5 | 2.9 | - | 2.5 | - | V |
| | | $V_{CC} = 5.0 \text{ V}; I_{OH} = -3 \text{ mA}$ | | 3.0 | 3.4 | - | 3.0 | - | V |
| | | $V_{CC} = 4.5 \text{ V}; I_{OH} = -32 \text{ mA}$ | | 2.0 | 2.4 | - | 2.0 | - | V |
| V_{OL} | LOW-level output voltage | V_{CC} = 4.5 V; I_{OL} = 64 mA; V_I = V_{IL} or V_{IH} | | - | 0.42 | 0.55 | - | 0.55 | V |
| $V_{OL(pu)}$ | power-up LOW-level output voltage | V_{CC} = 5.5 V; I_O = 1 mA; V_I = GND or V_{CC} | <u>[1]</u> | - | 0.13 | 0.55 | - | 0.55 | V |
| I _I | input leakage current | V_{CC} = 5.5 V; V_I = GND or 5.5 V | | - | ±0.01 | ±1.0 | - | ±1.0 | μΑ |
| I _{OFF} | power-off leakage current | $V_{CC} = 0 \text{ V}; \text{ V}_{I} \text{ or } \text{V}_{O} \le 4.5 \text{ V}$ | | - | ±5.0 | ±100 | - | ±100 | μΑ |
| I _{O(pu/pd)} | power-up/power-down output current | V_{CC} = 2.0 V; V_{O} = 0.5 V; V_{I} = GND or V_{CC} ; \overline{OE} n HIGH | [2] | - | ±5.0 | ±50 | - | ±50 | μΑ |
| l _{OZ} | OFF-state output current | V_{CC} = 5.5 V; V_I = V_{IL} or V_{IH} | | | | | | | |
| | | V _O = 2.7 V | | - | 5.0 | 50 | - | 50 | μΑ |
| | | V _O = 0.5 V | | - | -5.0 | -50 | - | -50 | μΑ |
| I _{LO} | output leakage current | HIGH-state; $V_O = 5.5 \text{ V}$; $V_{CC} = 5.5 \text{ V}$; $V_I = \text{GND or } V_{CC}$ | | - | 5.0 | 50 | - | 50 | μΑ |
| lo | output current | $V_{CC} = 5.5 \text{ V}; V_{O} = 2.5 \text{ V}$ | [3] | -180 | -80 | -50 | -180 | -50 | mΑ |
| I _{CC} | supply current | V_{CC} = 5.5 V; V_I = GND or V_{CC} | | | | | | | |
| | | outputs HIGH-state | | - | 0.5 | 250 | - | 250 | μΑ |
| | | outputs LOW-state | | - | 25 | 38 | - | 38 | mΑ |
| | | outputs disabled | | - | 0.5 | 250 | - | 250 | μΑ |
| Δl _{CC} | additional supply current | per input pin; V_{CC} = 5.5 V; one input at 3.4 V; other inputs at V_{CC} or GND | <u>[4]</u> | - | 0.5 | 1.5 | - | 1.5 | mA |
| Cı | input capacitance | $V_I = 0 \text{ V or } V_{CC}$ | | - | 4 | - | - | - | pF |
| Co | output capacitance | outputs disabled; $V_O = 0 \text{ V or } V_{CC}$ | | - | 7 | - | - | - | pF |

^[1] For valid test results, data must not be loaded into the flip-flops (or latches) after applying the power.

^[2] This parameter is valid for any V_{CC} between 0 V and 2.1 V with a transition time of up to 10 ms. For V_{CC} = 2.1 V to V_{CC} = 5 V \pm 10 %, a transition time of up to 100 μ s is permitted.

^[3] Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

^[4] This is the increase in supply current for each input at 3.4 $\rm V.$

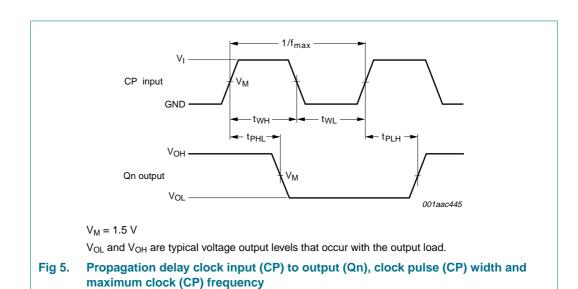
10-bit D-type flip-flop; positive-edge trigger; 3-state

10. Dynamic characteristics

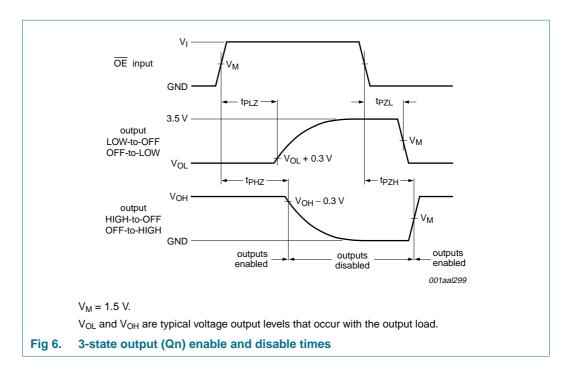
Table 7. Dynamic characteristics *GND = 0 V; for test circuit, see Figure 8.*

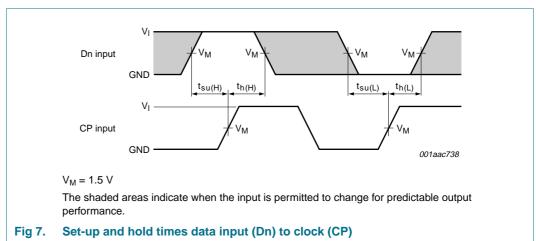
| Symbol | Parameter | Conditions | 25 °C; | V _{CC} = | 5.0 V | | o +70 °C; V ± 0.5 V | Unit |
|--------------------|-------------------------------------|-------------------------|--------|-------------------|-------|-----|------------------------|------|
| | | | Min | Тур | Max | Min | Max | |
| t _{PLH} | LOW to HIGH propagation delay | CP to Qn; see Figure 5 | 2.1 | 4.1 | 5.6 | 2.1 | 6.2 | ns |
| t _{PHL} | HIGH to LOW propagation delay | CP to Qn; see Figure 5 | 2.8 | 4.6 | 6.2 | 2.8 | 6.7 | ns |
| t _{PZH} | OFF-state to HIGH propagation delay | OEn to Qn; see Figure 6 | 1.0 | 3.0 | 4.5 | 1.0 | 5.3 | ns |
| t _{PZL} | OFF-state to LOW propagation delay | OEn to Qn; see Figure 6 | 2.2 | 4.1 | 5.6 | 2.2 | 6.3 | ns |
| t _{PHZ} | HIGH to OFF-state propagation delay | OEn to Qn; see Figure 6 | 2.7 | 4.7 | 6.2 | 2.7 | 6.7 | ns |
| t_{PLZ} | LOW to OFF-state propagation delay | OEn to Qn; see Figure 6 | 2.3 | 4.6 | 6.1 | 2.3 | 6.5 | ns |
| t _{su(H)} | set-up time HIGH | Dn to CP; see Figure 7 | 2.1 | 0.5 | - | 2.1 | - | ns |
| t _{su(L)} | set-up time LOW | Dn to CP; see Figure 7 | 2.1 | 0.3 | - | 2.1 | - | ns |
| t _{h(H)} | hold time HIGH | Dn to CP; see Figure 7 | 1.3 | 0 | - | 1.3 | - | ns |
| t _{h(L)} | hold time LOW | Dn to CP; see Figure 7 | 1.3 | -0.3 | - | 1.3 | - | ns |
| t _{WH} | pulse width HIGH | CP; see Figure 5 | 2.9 | 1.8 | - | 2.9 | - | ns |
| t_{WL} | pulse width LOW | CP; see Figure 5 | 3.8 | 2.8 | - | 3.8 | - | ns |
| f _{max} | maximum frequency | see Figure 5 | 125 | 185 | - | 125 | - | MHz |

11. Waveforms

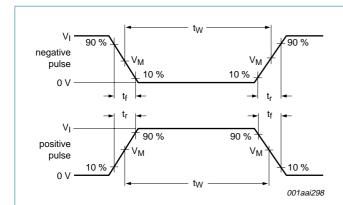


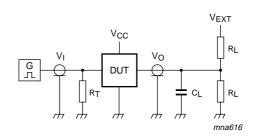
10-bit D-type flip-flop; positive-edge trigger; 3-state





10-bit D-type flip-flop; positive-edge trigger; 3-state





a. Input pulse definition

b. Test circuit

Test data and V_{EXT} levels are given in <u>Table 8</u>.

R_L = Load resistance.

C_L = Load capacitance including jig and probe capacitance.

 R_T = Termination resistance should be equal to output impedance Z_0 of the pulse generator.

 V_{EXT} = Test voltage for switching times.

Fig 8. Test circuit for measuring switching times

Table 8. Test data

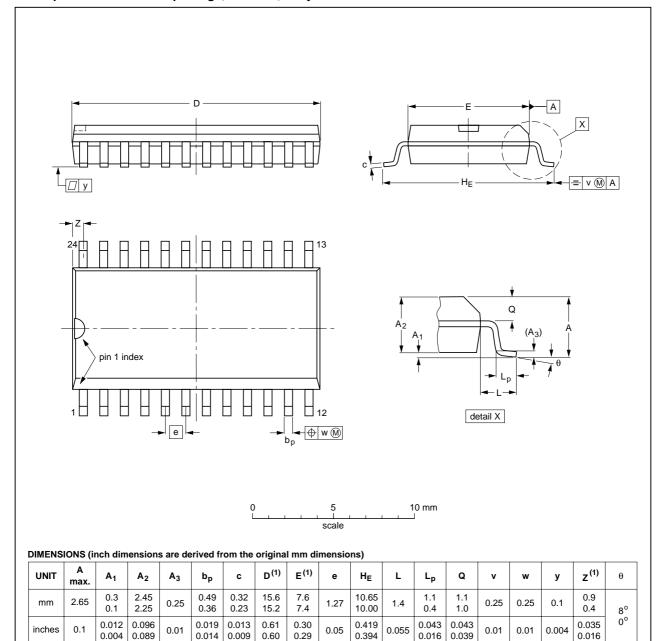
| Input | | | | Load | | V _{EXT} | | | |
|-------|-------------------------------|--------|---------------------------------|----------------|----------------|-------------------------------------|-------------------------------------|-------------------------------------|--|
| VI | f _I t _W | | t _r , t _f | C _L | R _L | t _{PHL} , t _{PLH} | t _{PZH} , t _{PHZ} | t _{PZL} , t _{PLZ} | |
| 3.0 V | 1 MHz | 500 ns | ≤ 2.5 ns | 50 pF | 500 Ω | open | open | 7.0 V | |

10-bit D-type flip-flop; positive-edge trigger; 3-state

12. Package outline

SO24: plastic small outline package; 24 leads; body width 7.5 mm

SOT137-1



Note

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

| OUTLINE | | REFER | EUROPEAN | ISSUE DATE | |
|----------|--------|--------|----------|------------|----------------------------------|
| VERSION | IEC | JEDEC | JEITA | PROJECTION | ISSUE DATE |
| SOT137-1 | 075E05 | MS-013 | | | -99-12-27 03-02-19 |

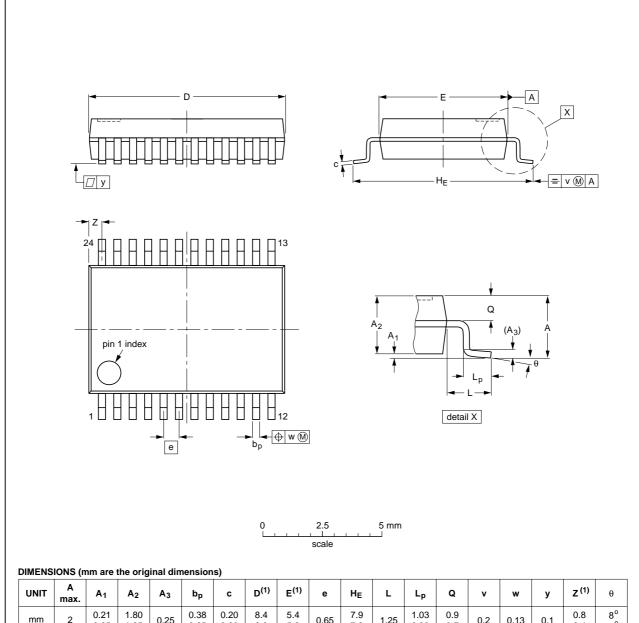
Fig 9. Package outline SOT137-1 (SO24)

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10-bit D-type flip-flop; positive-edge trigger; 3-state

SSOP24: plastic shrink small outline package; 24 leads; body width 5.3 mm

SOT340-1



| | | | | | | -, | | | | | | | | | | | | |
|------|-----------|----------------|----------------|----------------|--------------|--------------|------------------|------------------|------|------------|------|--------------|------------|-----|------|-----|------------------|----------|
| UNIT | A max. | A ₁ | A ₂ | A ₃ | bp | С | D ⁽¹⁾ | E ⁽¹⁾ | е | HE | L | Lp | Q | v | w | у | Z ⁽¹⁾ | θ |
| mm | 2 | 0.21 0.05 | 1.80 1.65 | 0.25 | 0.38 0.25 | 0.20 0.09 | 8.4 8.0 | 5.4 5.2 | 0.65 | 7.9 7.6 | 1.25 | 1.03 0.63 | 0.9 0.7 | 0.2 | 0.13 | 0.1 | 0.8 0.4 | 8° 0° |

Note

1. Plastic or metal protrusions of 0.2 mm maximum per side are not included.

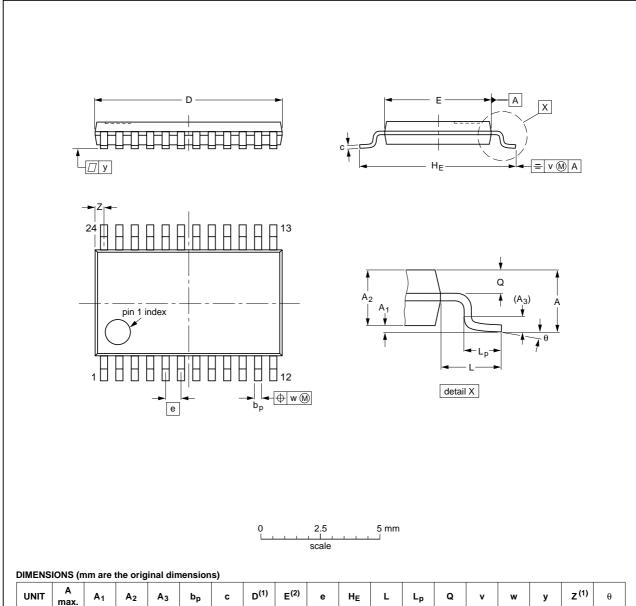
| OUTLINE | | REFER | EUROPEAN | ISSUE DATE | | |
|----------|-----|--------|----------|------------|------------|---------------------------------|
| VERSION | IEC | JEDEC | JEITA | | PROJECTION | ISSUE DATE |
| SOT340-1 | | MO-150 | | | | 99-12-27 03-02-19 |

Fig 10. Package outline SOT340-1 (SSOP24)

10-bit D-type flip-flop; positive-edge trigger; 3-state

TSSOP24: plastic thin shrink small outline package; 24 leads; body width 4.4 mm

SOT355-1



| UNIT | A max. | A ₁ | A ₂ | A ₃ | bp | С | D ⁽¹⁾ | E ⁽²⁾ | е | HE | L | Lp | Q | v | w | у | z ⁽¹⁾ | θ |
|------|-----------|----------------|----------------|----------------|--------------|------------|------------------|------------------|------|------------|---|--------------|------------|-----|------|-----|------------------|----------|
| mm | 1.1 | 0.15 0.05 | 0.95 0.80 | 0.25 | 0.30 0.19 | 0.2 0.1 | 7.9 7.7 | 4.5 4.3 | 0.65 | 6.6 6.2 | 1 | 0.75 0.50 | 0.4 0.3 | 0.2 | 0.13 | 0.1 | 0.5 0.2 | 8° 0° |

Notes

- 1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
- 2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

| REFERENCES | | | EUROPEAN | ISSUE DATE | |
|------------|--------|-----------|-----------------|-----------------|---------------------------------|
| IEC | JEDEC | JEITA | | PROJECTION | ISSUE DATE |
| | MO-153 | | | | 99-12-27 03-02-19 |
| | IEC | IEC JEDEC | IEC JEDEC JEITA | IEC JEDEC JEITA | IEC JEDEC JEITA PROJECTION |

Fig 11. Package outline SOT355-1 (TSSOP24)

10-bit D-type flip-flop; positive-edge trigger; 3-state

13. Abbreviations

Table 9. Abbreviations

| Acronym | Description |
|---------|-------------------------------------------------|
| BiCMOS | Bipolar Complementary Metal-Oxide Semiconductor |
| DUT | Device Under Test |
| ESD | ElectroStatic Discharge |
| НВМ | Human Body Model |
| MM | Machine Model |

14. Revision history

Table 10. Revision history

| Document ID | Release date | Data sheet status | Change notice | Supersedes | |
|----------------|---------------------------------------------------------------------------------------------------------------------------------------------|------------------------------------|------------------------|----------------------------|--|
| 74ABT821_3 | 20100225 | Product data sheet | - | 74ABT821_2 | |
| Modifications: | The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. | | | | |
| | Legal texts have been adapted to the new company name where appropriate. | | | | |
| | DIP 24 (SOT22 "Package outling") | 22-1) package removed from ne". | Section 3 "Ordering in | nformation" and Section 12 | |
| 74ABT821_2 | 20050412 | Product specification | - | 74ABT821 | |
| 74ABT821 | 19950906 | Product specification | - | - | |
| | | | | | |

10-bit D-type flip-flop; positive-edge trigger; 3-state

15. Legal information

15.1 Data sheet status

| Document status[1][2] | Product status[3] | Definition |
|--------------------------------|-------------------|---------------------------------------------------------------------------------------|
| Objective [short] data sheet | Development | This document contains data from the objective specification for product development. |
| Preliminary [short] data sheet | Qualification | This document contains data from the preliminary specification. |
| Product [short] data sheet | Production | This document contains the product specification. |

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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10-bit D-type flip-flop; positive-edge trigger; 3-state

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